

Intro to Photolithography Quiz

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Quiz ideas

- 1) A Photo cluster is comprised of which TWO of the following tools?
Select the best answer.
 - A. Scanner and CD SEM
 - B. CD SEM and Track
 - C. Dose and Focus
 - D. Track and Scanner
- 2) How is dose typically measured in Photolithography?
 - A. J/nm^2 (Joules per nanometer square)
 - B. mJ/cm^2 (mili Joules per centimeter square)
 - C. Lm/mm^2 (lumens per millimeter square)
 - D. kW/m^2 (kilo Watts per meter square)
- 3) In what tool does the develop process take place?
 - A. CD SEM
 - B. Registration tool
 - C. Track
 - D. Scanner
- 4) What are the primary functions of the scanner?
 - A. Resist dispense and develop
 - B. Inspect and measurement
 - C. Align and expose
 - D. Strip and clean
- 5) Contamination on the backside of a wafer or on the surface of the chuck can cause which defect?
 - A. Focus spot
 - B. Foreign material
 - C. Resist bubble
 - D. Resist toppling
- 6) Resist features that have a high aspect ratio can cause which of the following defects?
 - A. Focus spots
 - B. Foreign material
 - C. Resist bubble
 - D. Resist toppling

Quiz ideas

- 7) What does a CD SEM tool typically measure?
- A. Resist adhesion
 - B. Resist thickness
 - C. Number, location and size of particles
 - D. Line width, space width, diameters
- 8) In photolithography, what term refers to the precise vertical position of the wafer where the projected image from the scanner lens is sharply formed?
- A. Numerical aperture
 - B. Resolution
 - C. Focal plane
 - D. Dose
- 9) What is defined as the smallest pattern that photo can print in the resist on the wafer?
- A. Numerical aperture
 - B. Resolution
 - C. Focus
 - D. Dose
- 10) What is the relationship between Wavelength and Resolution?
- A. Wavelength is directly proportional to Resolution
 - B. Wavelength is inversely proportional to Resolution
 - C. There is no relationship between Wavelength and Resolution
- 11) Which of the following measures the offset between the new resist pattern and a prior critical structure of interest?
- A. Registration
 - B. Resist thickness
 - C. Number, location and size of particles
 - D. Line width, space width, diameters
- 12) Which of the following processes is most similar to the Photolithography process?
- A. Remote control communication - uses radio waves transmitted through air to encode and send information
 - B. Plastic molding - uses high temperature and highly compressive forces to mold and reshape a material
 - C. Traditional photography - uses light through a lens, which is absorbed by a material that is photosensitive
 - D. Convection Oven - heating substrates through the circulation of air at a high temperature

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